# Two-qubit near-field microwave gates on 43Ca+

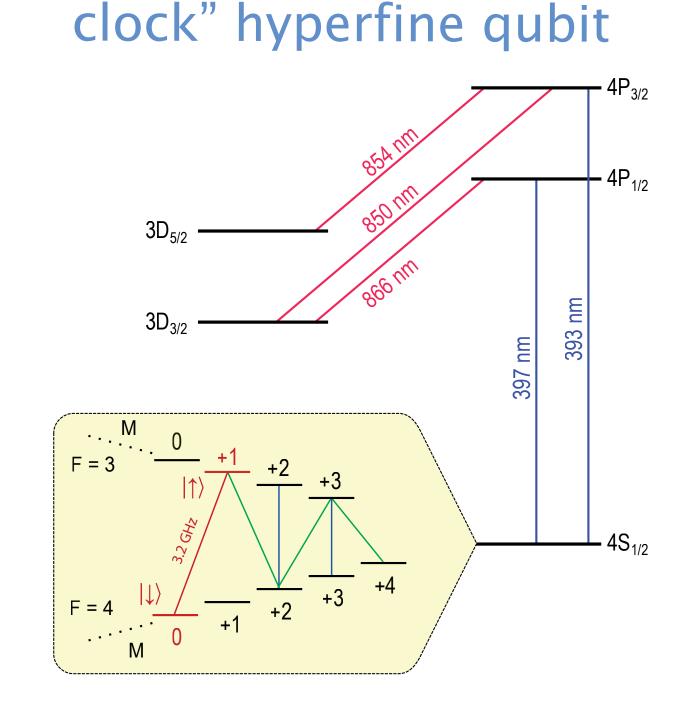
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# Introduction

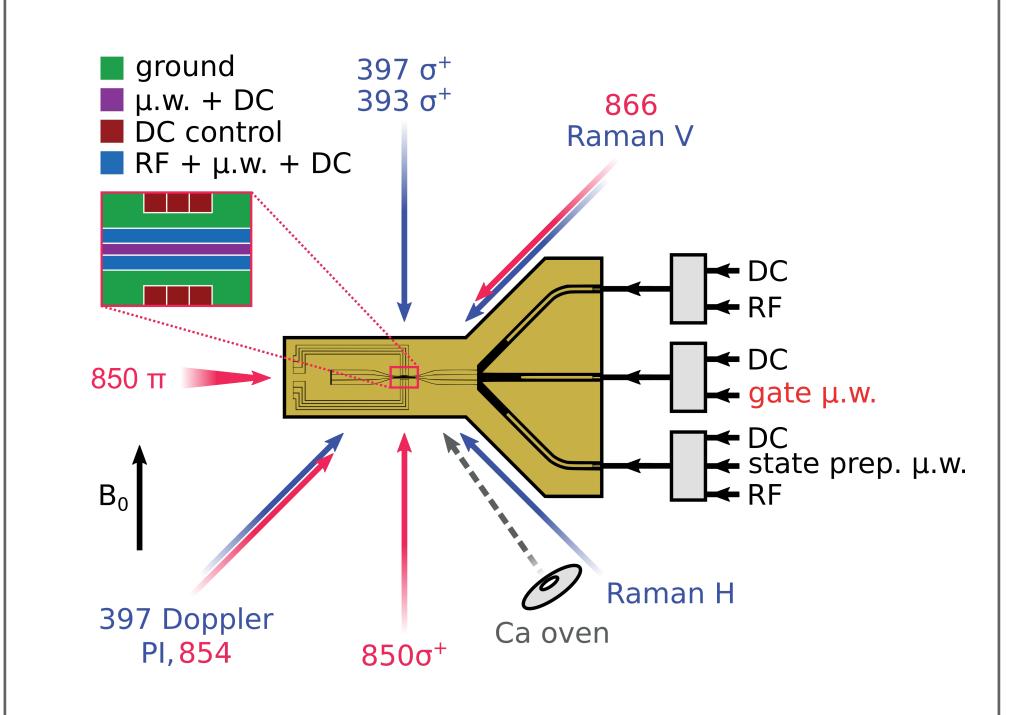
In order to build a scalable quantum computer, accurate qubit state preparation and single-shot readout, long coherence times, and high-fidelity single- and two-qubit gates must all be possible. We present results that fulfil these requirements using 43Ca+ trapped-ion qubits. We use near-field microwave control in a surface-electrode ion trap to achieve a single-qubit gate fidelity of 99.9999%. Using a novel dynamically-decoupled gate method, we achieve a two-qubit gate fidelity of 99.7%. We also achieve a coherence time of  $T_2^* \approx 50$ s and a state preparation and measurement (SPAM) fidelity of 99.93%. In addition to these results, we present preliminary designs for a next-generation experimental system. Technical improvements include cryogenic cooling, ex-situ argon ion surface cleaning, passive microwave field nulling, ion shuttling and ion chain splitting.

# Intermediate-field "atomic



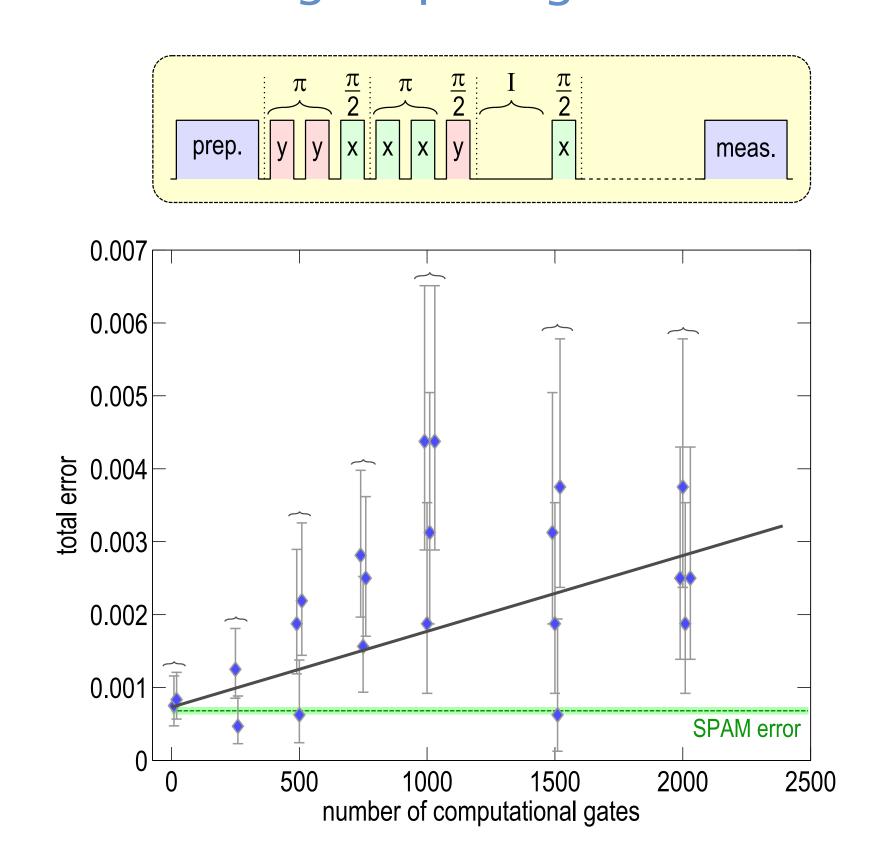
- Qubit transition frequency independent of magnetic field at 146G - We obtain a coherence time of  $T_2^* = 50(10)s$
- Initialised in  $4S_{1/2}$  (F = 4, M = +4) by several cycles of  $397\sigma^+$  optical pumping and microwave "reclaiming"  $\pi$ –pulses (shown in blue)
- Qubit prepared using microwave  $\pi$ –pulses (shown in green)
- Readout achieved by "shelving" one qubit state in 3D<sub>5/2</sub>
- State preparation and measurement (SPAM) error of 6.8(5)x10<sup>-4</sup> achieved - See [Harty et al. PRL (2014)]

# Current trap design



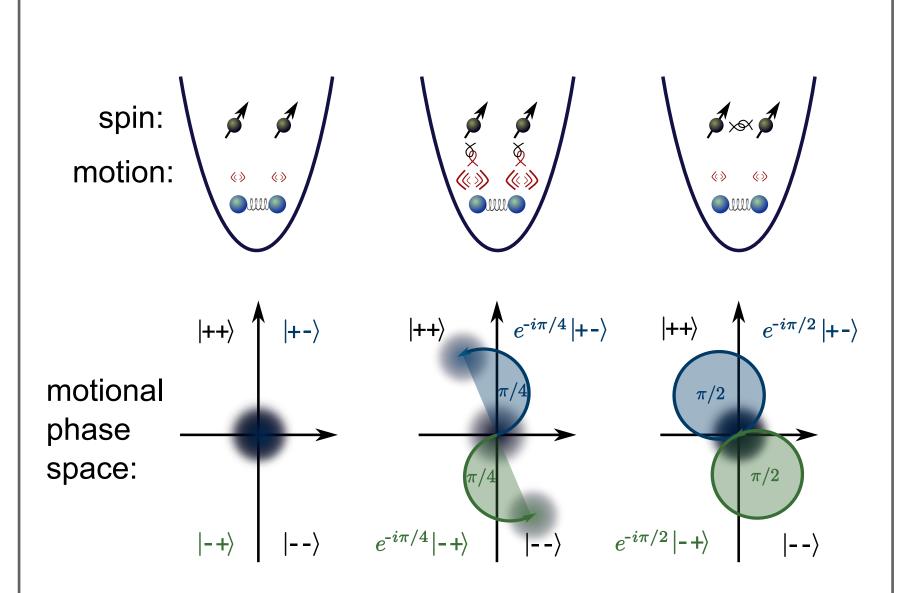
- Uses oscillating currents in an rf surface trap to apply near-field microwaves to ions
- Features integrated microwave circuitry [Allcock et al. APL (2013)] - Capable of performing both single- and two-qubit gates

#### Single-qubit gates



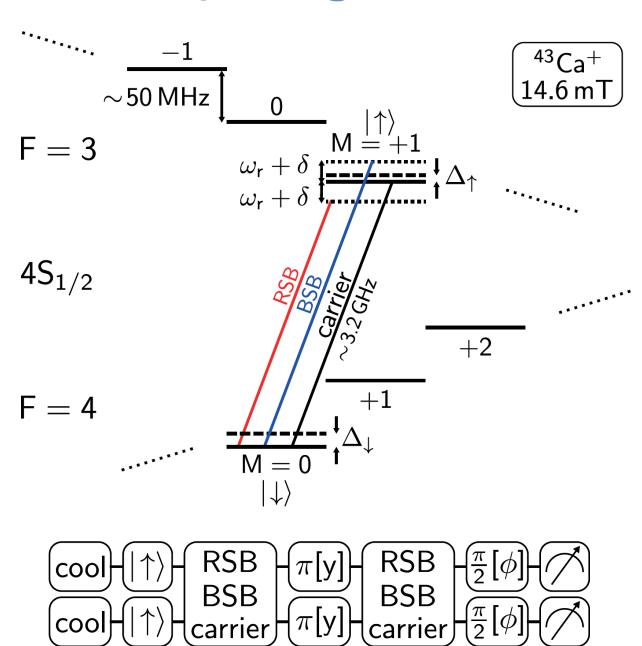
- Randomised benchmarking used to measure average single-qubit gate error
- Average gate error of  $1.0(3)\times10^{-6}$  [Harty et al. PRL (2014)]

## Entanglement generation



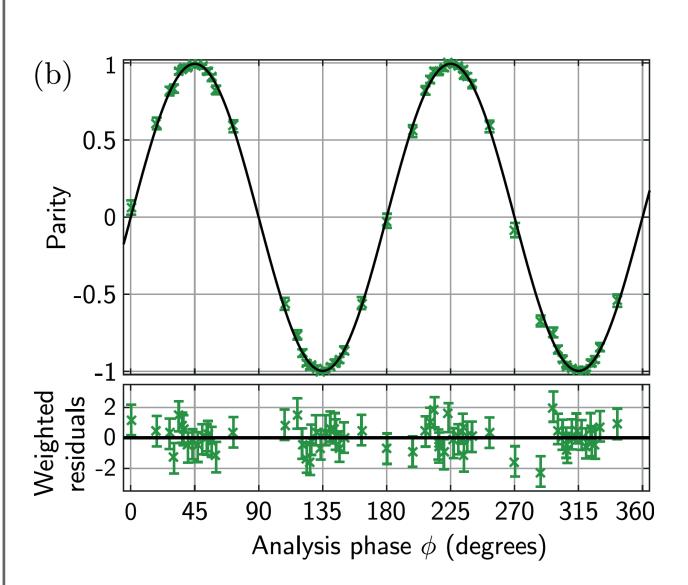
- We generate entanglement by inducing different geometric phases on different parts of the wavefunction  $(|\pm\rangle \equiv (|\downarrow\rangle \pm |\uparrow\rangle)/\sqrt{2}$
- Operation achieved using near-field microwave scheme proposed in [Ospelkaus et al. PRL (2008)] - Scheme first demonstrated at NIST [Ospelkaus et al. Nature (2011)]

# Two-qubit gate scheme



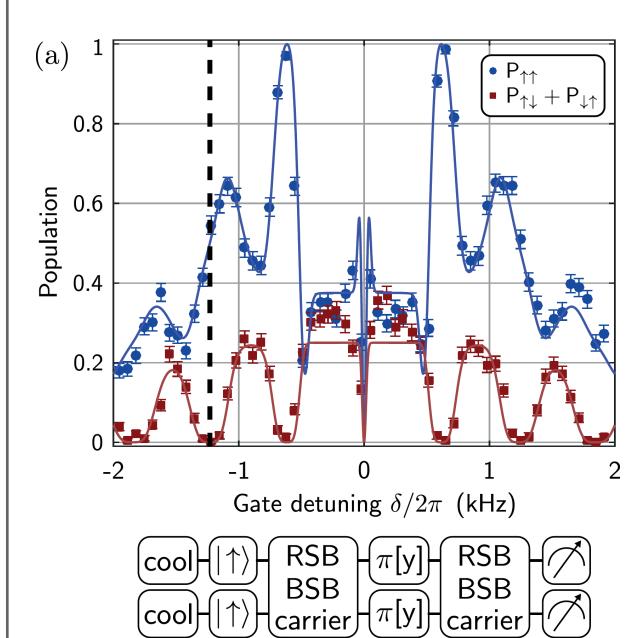
- Bichromatic field with frequencies near first red and blue sidebands as for Mølmer-Sørensen gates
- Dynamical decoupling with a  $\sigma_{\nu}$  carrier drive protects against fluctuations in AC Zeeman shift  $(\Delta, -\Delta)$
- Carrier drive Rabi frequency of 4kHz compared with 436Hz for single-ion sideband
- $\pi[y]$  pulse at midpoint to refocus qubit populations

# Two-qubit gate results



- Two-qubit gate fidelity of 99.7(1)% [Harty et al. arXiv (2016)]
- See also work done with far-field microwaves at Siegen [Khromova et al. PRL (2012)] and Sussex [Weidt et al. arXiv (2016)]

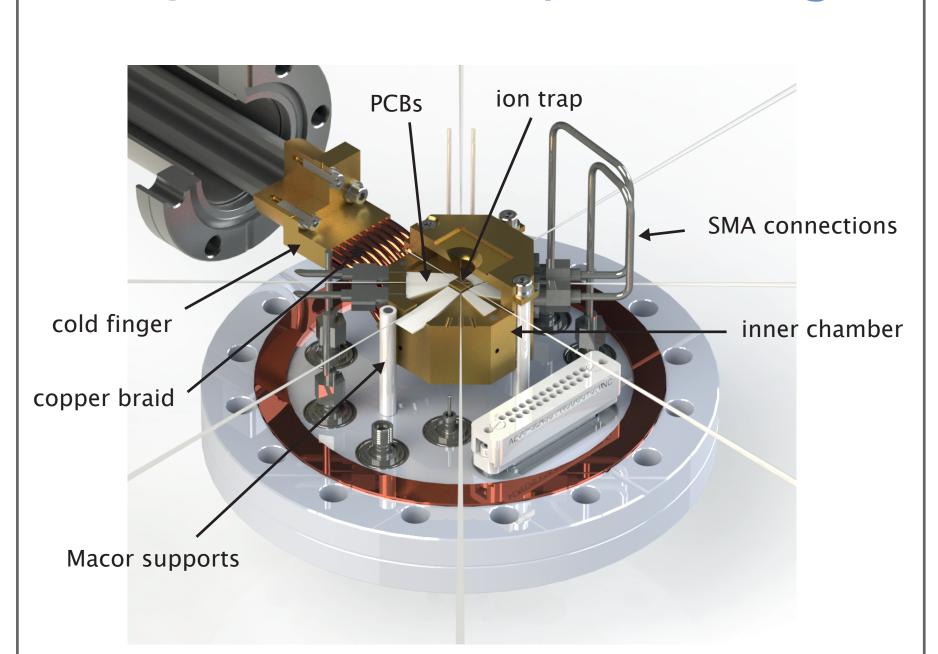
# Detuning scans



- Plot shows the different two-qubit populations as a function of microwave detuning from sidebands
- Dashed line indicates detuning used for gate
- Compared with simulations to calibrate gate parameters

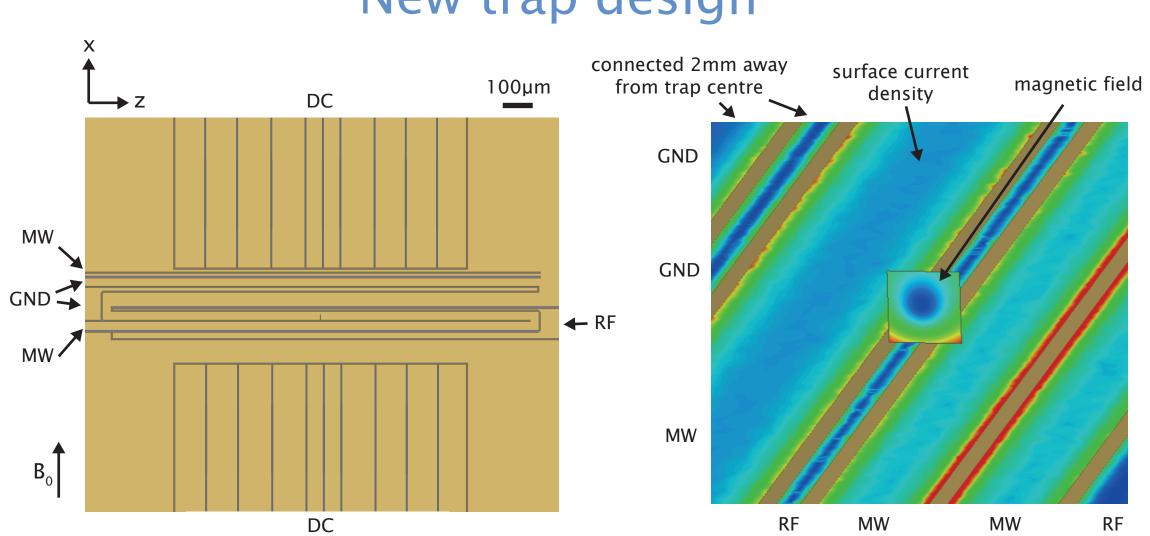
### Next-generation system

#### Cryogenic vacuum system design



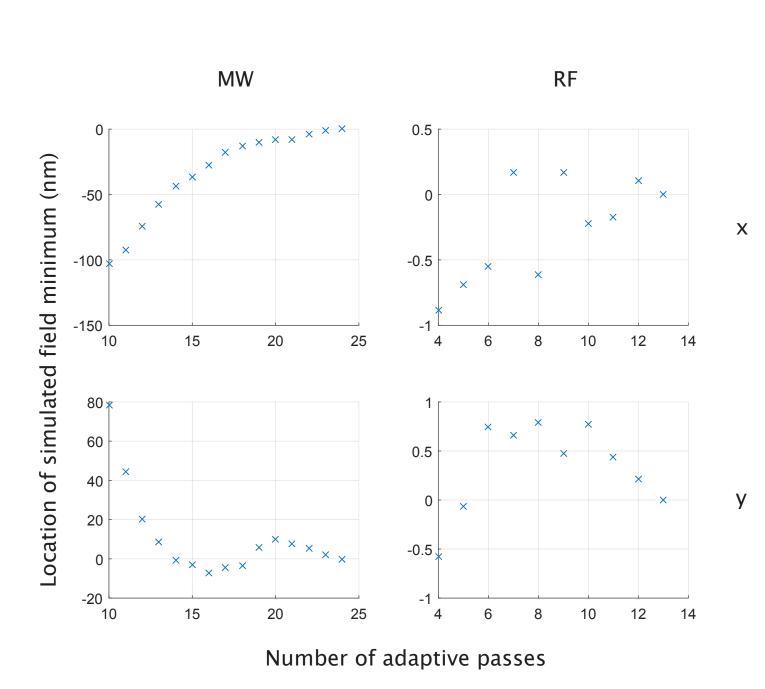
 Cryogenic cooling with Janis ST–400 cryostat - Cold finger thermally connected to inner chamber with copper braid to minimise vibrational coupling - Inner chamber attached to base of vacuum chamber with Macor supports to minimise thermal load Ex-situ argon ion surface cleaning

## New trap design



- Single meander-shaped electrode for entangling microwave signals (see [Carsjens et al. App. Phys. B (2014)] and [Wahnschaffe et al. arXiv (2016)] for previous work on this idea)
- Second microwave electrode for single-qubit gates and small adjustments to two-qubit gate field
- DC electrodes for transporting between three trapping zones and separating ions in the central zone
- Asymmetric RF electrode geometry
- Includes a cut in the ground plane (the two parts are connected 2mm away from the trap centre, to the left of region shown above) to manipulate the microwave return currents

#### Simulation results



- RF electric and microwave magnetic field minima fixed by trap geometry, so need to ensure alignment during design process
- HFSS simulations give precision error of <100nm (see plots)</li>
- Trap fabrication tolerances expected to give misalignment of <1 µm
- Corresponding ratio B'/B of ~1x10<sup>5</sup> m<sup>-1</sup> for ion at RF null, compared to  $9x10^3$  m<sup>-1</sup> for current trap













